Docket: 0756-2321

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re New Patent Application of

Masaaki HIROKI

)

Japanese Priority Application No. 2000-168143

) Attn: Applications

Japanese Priority Date: June 5, 2000

Branch

For: DEVICE FOR INSPECTING ELEMENT

SUBSTRATES AND METHOD OF

INSPECTION USING THIS DEVICE

) Date: May 30, 2001

PRELIMINARY AMENDMENT

Honorable Commissioner for Patents

Washington, D.C. 20231

Sir:

Please preliminarily amend the subject application as follows:

IN THE SPECIFICATION:

Please amend the specification as follows: Please note that the specification is presented below in its amended form. It is further presented as an Attachment to the Amendment whereby the amendments to the specification are outlined using the conventional method of bracketing and underlining.

Page 11, under the heading BRIEF DESCRIPTION OF THE DRAWINGS, please amend paragraphs one and two as follows:

Figs. 1 (A), 1(B), and 1(C) are diagrams illustrating an inspection device of this invention;

